

<b>Notice of References Cited</b>	Application/Control No. 10/534,019	Applicant(s)/Patent Under Reexamination MIYASAKA, ATSUSHI	
	Examiner Steven D. Maki	Art Unit 1733	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,986,372	01-2006	Below, Todd	152/209.15
*	B	US-6,079,464	06-2000	Hatakenaka et al.	152/209.24
*	C	US-5,964,267	10-1999	Poque et al.	152/209.21
*	D	US-5,658,404	08-1997	Brown et al.	152/209.21
*	E	US-4,926,919	05-1990	Hopkins et al.	152/DIG.3
*	F	US-2005/0211353	09-2005	Bogenschuetz et al.	152/209.1
*	G	US-2002/0026972	03-2002	Ochi, Naoya	152/209.28
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2002-293109	10-2002	Japan		-----
	O	11-091315	04-1999	Japan		-----
	P	02-114006	04-1990	Japan		-----
	Q	11-334320	12-1999	Japan		-----
	R	2001-146104	05-2001	Japan		-----
	S	WO 03/013881	02-2003	WIPO		-----
	T	890457	01-1999	Europe		-----

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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